

PROCEEDINGS OF SPIE

# ***Automated Visual Inspection and Machine Vision VI***

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*Editors*

**26–27 June 2025  
Munich, Germany**

*Sponsored and Published by*  
SPIE

**Volume 13572**

Proceedings of SPIE 0277-786X, V. 13572

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Author(s), "Title of Paper," in *Automated Visual Inspection and Machine Vision VI*, edited by Michael Heizmann, Thomas Längle, Proc. of SPIE 13572, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510690523

ISBN: 9781510690530 (electronic)

Published by

**SPIE**

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)

[SPIE.org](http://SPIE.org)

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